

<b>Notice of References Cited</b>	Application/Control No. 10/807,857		Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
	Examiner Gabriel L. Chu		Art Unit 2114	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0041184	02-2003	Tervo, Vesa	710/1
*	B	US-2003/0105890	06-2003	Sakuma, Takeshi	710/1
*	C	US-2003/0155417	08-2003	Fairman, Bruce Alan	235/381
*	D	US-2004/0030912	02-2004	Merkle et al.	713/200
*	E	US-2005/0005114	01-2005	Medvinsky, Alexander	713/168
*	F	US-2005/0177591	08-2005	Kanda et al.	707/102
*	G	US-2005/0193236	09-2005	Stager et al.	714/006
*	H	US-4,808,802	02-1989	Kano, Mitsunari	235/380
*	I	US-5,689,699	11-1997	Howell et al.	707/9
*	J	US-5,781,630	07-1998	Huber et al.	713/178
*	K	US-6,393,126	05-2002	van der Kaay et al.	380/241
*	L	US-6,915,398	07-2005	Matsubara et al.	711/163
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.